

Notice of References Cited

Application/Control No.

10/694,737

Applicant(s)/Patent Under
Reexamination
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Examiner

Jaime Cardenas-Navia

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0133444 A1	09-2002	Sankaran et al.	705/36
*	B	US-2002/0161674 A1	10-2002	Scheer, Robert H.	705/28
*	C	US-2003/0088449 A1	05-2003	Menninger, Anthony Frank	705/8
*	D	US-2004/0254825 A1	12-2004	Hsu et al.	705/008
*	E	US-2005/0060164 A1	03-2005	ELI BERL ILLION, BRIAN	705/001
*	F	US-2005/0075920 A1	04-2005	Li et al.	705/010
*	G	US-2006/0246436 A1	11-2006	Ohno et al.	435/006
*	H	US-7,236,940 B2	06-2007	Chappel, Oscar A.	705/10
*	I	US-2007/0192160 A1	08-2007	Nephew et al.	705/010
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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	V				
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	X				

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